


<b>Search Notes</b>  	<b>Application/Control No.</b>  10532446	<b>Applicant(s)/Patent Under Reexamination</b>  DE HAEN ET AL.
	<b>Examiner</b>  BRANDON J FETTEROLF	<b>Art Unit</b>  1642

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
WEST (see attached) PGPUB/USPAT/EPAB	10/14/08	BF
Inventor Search	10/14/08	BF
WEST (See attached) PGPUB/USPAT/EPAB	4/26/09	BF
Google/Scholar/Patents: KW TCEP (Syn), reduction, Fab frag, antibod.,	4/26/09	BF
Inventor Search	4/26/09	BF

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/BRANDON J FETTEROLF/ Primary Examiner.Art Unit 1642
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